MSE-624

CCMX Advanced Course - Atomic Force Microscopy (AFM): Theory and Practice

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Cursus	Sem.	Type
Materials Science and Engineering		Obl.

Language of teaching	English
Credits	1
Session	
Exam	Oral
Workload	30h
Hours	**16**
Courses	5
TP	11
Number of positions	**24**

Remark

Postponed until further notice

Summary

The course features a theoretical introduction to Atomic Force Microscopy techniques and hands-on training for all levels of experience, from beginners to more advanced users.

Content

Please find the information on the following link :
http://www.ccmx.ch/courses-and-events/article/2015/11/ccmx-advanced-course-3/

Note

Please register with CCMX

Keywords

Atomic Force Microscopy, Scanning Force Microscopy, contact mode, intermittent contact mode, peak force mode, true non-contact mode in vacuum.

Learning Prerequisites

Recommended courses

materials sciences, physics, chemistry

Assessment methods

Oral exam

Resources

Websites

- http://www.ccmx.ch/courses-and-events/news-single/article/189/60/